Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination FALKNER, KEMP E.	
10/785,231		
Examiner	Art Unit	
Matthew O. Savage	1724	

SEARCHED					
Class	Subclass	Date	Examiner		
261	76				
261	DIG. 75				
417	186, 192				
137	599.12				
137	601.2				
137	894				
210	130, 136				
210	195.2				
210	220				
210	321.69				
Search	Updated	6/8/2006	mg		

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
76				
599.12				
220	6/8/2006	mg		
	76 599.12	76 599.12		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
Consulted Richard Chiesa of class 261 and John Rivell of class 137. Conducted an interference search and an inventor search.	6/8/2006	mg		